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SERIAL NUMBER 10/664,440	FILING DATE 09/18/2003	CLASS 250	GROUP ART UNIT 2881	ATTORNEY DOCKET NO. 514802002600	
APPLICANTS					
Mitsuyuki Asaki, Tokyo, JAPAN; Akira Kintaka, Tokyo, JAPAN;					
** CONTINUING DATA * * * * * <i>J. mnd</i> ** FOREIGN APPLICATIONS * * * * * <i>J. mnd</i> JAPAN 2002-293717 10/07/2002					
IF REQUIRED, FOREIGN FILING LICENSE GRANTED ** 12/13/2003					
Foreign Priority claimed <input checked="" type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 (a-d) conditions met <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after Allowance Verified and Acknowledged <i>J. mnd</i> Examiner's Signature Initials		STATE OR COUNTRY JAPAN	SHEETS DRAWING 6	TOTAL CLAIMS 13	INDEPENDENT CLAIMS 3
ADDRESS David L. Fehrman Morrison & Foerster LLP 35th Floor 555 W. 5th Street Los Angeles , CA 90013					
TITLE Pattern width measuring apparatus, pattern width measuring method, and electron beam exposure apparatus					
FILING FEE	FEES: Authority has been given in Paper No. _____ to charge/credit DEPOSIT ACCOUNT No. _____ for following:		<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees (Filing) <input type="checkbox"/> 1.17 Fees (Processing Ext. of time)		